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Application/Control No.	Applicant(s)/Patent under Reexamination
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SEARCH NO (INCLUDING SEARCH	TES STRATEGY)	)
	DATE	EXMR
Consulted with Jingge Wu, AU 2623	10/11/2005	DMC
text search	10/12/2005	DMC
Consulted with Jingge Wu, AU 2623	10/13/2005	DMC
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